PCN N	umbe	r:	20	20161010001						PCN Date:	Oct 12	2, 2016	
Title:		ualification evices	of A	ASEN as	Ado	ditional <i>I</i>	Assembly	and Tes	st Sit	te 1	for Select US	ON Pac	:kage
Custor	mer Co	ntact:	PCI	N Manage	<u>r</u>	Dept:		Quality	Ser	vic	es		
Proposed 1 st Ship Date			e:	Jan 12,	20	1 /	timated ailabilit	Sample	D	ate	e Provided at Jest	: Sampl	е
Chang	e Type	 2:											
	ssembl					Desigi	n				Wafer Bum	p Site	
		y Process						Wafer Bump Material					
		y Materials	5		Ī		umber ch	nange		Ħ	Wafer Bum		
		cal Specifi		n	$\overline{\boxtimes}$	Test S					Wafer Fab	•	
□ Pi	acking/	Shipping/l	_abe	eling		Test P	rocess				Wafer Fab	Materia	ls
											Wafer Fab	Process	;
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		of Change											
and Te	st Site		devi	ces liste	d ir	n the "Pr					N as Additior Current ass		
Assen	nbly Sit	e Assem	bly S	ite Origi	n	Assemb	ly Countr	y Code		As	sembly Site C	ity	
Ca	rsem		CR	S			MY				Jelapang		
UTAC	Thailan	d	NS	E			TH				Bangkok		
A	SEN		AS	N			CN				Suzhou		
Materi Group		erences:											
				NS	SE			ASEN					
Mou	ınt Con	npound		PZ0	PZ0039		9 14002381		2				
Мо	ld com	pound		CZ0	Z0140		1801512111		1				
Group	2 Dev	ice:					I				•		
				Carsem				ASEN					
	Wire ty	/pe		1.3m	il A	.u	1.0mil Cu						
	Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.					d with							
Reaso	n for (Change:											
Continu	uity of	supply.											
1) To a	To align with world technology trends and use wiring with enhanced mechanical and												
electrical properties													
·													
2) Maximize flexibility within our Assembly/Test production sites.													
3) Cu is easier to obtain and stock													
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):													
None													
Anticip	pated	impact or	Ma) ec	laration	1						
Anticipated impact on Material Declaration No Impact to the Material Declaration Material Declaration Material Declaration Material Declarations or Product Content reports are driven for production data and will be available following the production release. Upon production release the revised reports can be obtained at the site link below http://www.ti.com/quality/docs/materialcontentsearch.tsp			uction an be										

Changes to product identification resulting from this PCN:

Assembly Site		
Carsem	Assembly Site Origin (22L)	ASO: CRS
UTAC Thailand	Assembly Site Origin (22L)	ASO: NSE
ASEN	Assembly Site Origin (22L)	ASO: ASN

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Group 1 Product Affected:

TPD2E001DRYR	TPD4S012DRYR
=====:::::	

Group 2 Product Affected:

DRV10863DSNR

Group 1: Qualification Report

Qualifying TPD4S012DRYR and TPD2E001DRYR at ASEN

Approve Date 14-Sep-2016

Product Attributes

Attributes	Qual Device: TPD2E001DRYR	Qual Device: TPD4S012DRYR	QBS Package Reference: SN74AVC4T245RSVR
Assembly Site	ASEN	ASEN	ASEN
Package Family	SON	SON	-
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	FFAB	FFAB	FFAB
Wafer Process	A3C10TPI	A3C10TPI	ASLC10

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TPD2E001DRYR	Qual Device: TPD4S012DRYR	QBS Package Reference: SN74AVC4T245RSVR
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	-	-	Pass
FLAM	Flammability (IEC 695-2-2)		3/15/0	-	3/15/0
FLAM	Flammability (UL 94V-0)		3/15/0	-	3/15/0
FLAM	Flammability (UL-1694)		3/15/0	-	3/15/0
HAST	Biased HAST, 130C/85%RH	96 Hours	1/77/0	-	3/231/0

⁻ Qual Devices qualified at LEVEL1-260C: TPD2E001DRYR, TPD4S012DRYR

HTOL	Life Test, 150C	300 Hours	1/77/0	-	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	3/231/0	3/231/0
PD	Physical Dimensions		3/15/0	-	3/15/0
SD	Solderability	Pb-Free	3/66/0	-	3/66/0
SD	Solderability	Pb	3/66/0	-	-
TC	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0	3/231/0
WBP	Bond Pull	Wires	3/228/0	3/228/0	-
WBP	Bond Strength	Wires	-	-	3/228/0
WBS	Ball Bond Shear	Wires	3/228/0	3/228/0	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of $0.7 \mathrm{eV}$: $150 \mathrm{C}/1 \mathrm{k}$ Hours, and $170 \mathrm{C}/420$ Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Group 2: Qualification Report

Qualify Second Source Assembly Site for DRV10863DSNR - ASEN
Approve Date 05-Oct-2016

Product Attributes

Attributes	Qual Device: DRV10863DSNR	QBS Product Reference: DRV10863BA	QBS Product Reference: DRV10863BB	QBS Process Reference: TPS62110RSA	QBS Package Reference: SN74HC595BRWN	QBS Package Reference: SN74HC595PWR.
Assembly Site	ASEN	CRS-CARSEM	CRS-CARSEM	CAR	ASEN	MLA (TIM)
Package Family	SON, 3 x 3 MM	SON	SON	QFN	X1QFN	TSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	-
Wafer Fab Supplier	MIHO 8	MH8	MH8	MIHO8	FFAB	FFAB
Wafer Process	LBC7	LBC7	LBC7	LBC7	ASLC10/P9742	ASLC10/P9742

- QBS: Qual By Similarity
- Qual Device DRV10863DSNR is qualified at LEVEL2-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DRV10863DSNR	QBS Product Reference: DRV10863BA	QBS Product Reference: DRV10863BB
AC	Autoclave 121C	96 Hours	3/231/0	1/77/0	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	-	Pass
ELFR	Early Life Failure Rate, 140C	48 Hours	-	-	-
FLAM	Flammability (IEC 695-2-2)		1/7/0	-	-
FLAM	Flammability (UL 94V-0)		1/7/0	-	-
FLAM	Flammability (UL-1694)		1/7/0	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-

HBM	ESD - HBM	2500 V	-	1/9/0	-
CDM	ESD - CDM	1000 V	-	1/3/0	1/3/0
HTOL	Life Test, 125C	1000 Hours	-	1/77/0	-
HTOL	Life Test, 140C	480 Hours	-	-	-
HTOL	Life Test, 150C	300 Hours	-	-	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	-	-
LU	Latch-up	(per JESD78)	-	2/12/0	2/12/0
PD	Physical Dimensions		3/15/0	-	-
SD	Surface Mount Solderability	Pb	2/48/0	-	-
SD	Surface Mount Solderability	Pb-Free	2/48/0	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	1/77/0	-
TS	Thermal Shock, -65/150C	500 Cycles	-	-	-
WBP	Bond Pull	Wires	-	-	-
WBS	Ball Bond Shear	Wires	-	-	-

Туре	Test Name / Condition	Duration	QBS Process Reference: TPS62110RSA	QBS Package Reference: SN74HC595BRWN	QBS Package Reference: SN74HC595PWR.
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	-
ED	Electrical Characterization	Per Datasheet Parameters	-	Pass	Pass
ELFR	Early Life Failure Rate, 140C	48 Hours	3/1881/0	-	-
FLAM	Flammability (IEC 695-2-2)		-	-	-
FLAM	Flammability (UL 94V-0)		-	-	-
FLAM	Flammability (UL-1694)		-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0	-
HBM	ESD - HBM	2500 V	-	-	-
CDM	ESD - CDM	1000 V	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-
HTOL	Life Test, 140C	480 Hours	3/231/0	-	-
HTOL	Life Test, 150C	300 Hours	-	6/462/0	1/77/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	2/231/0	-
LU	Latch-up	(per JESD78)	3/15/0	-	1/6/0
PD	Physical Dimensions		-	3/15/0	-
SD	Surface Mount Solderability	Pb	-	3/66/0	-
SD	Surface Mount Solderability	Pb-Free	-	3/66/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	6/462/0	-
TS	Thermal Shock, -65/150C	500 Cycles	3/231/0	-	-
WBP	Bond Pull	Wires	-	3/228/0	-
WBS	Ball Bond Shear	Wires	-	3/228/0	

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com